









Instruments

TS3L110

ZHCSJR6B-SEPTEMBER 2004-REVISED OCTOBER 2019

TS3L110 四路 SPDT 高带宽 10/100 Base-T LAN 开关 差分 8 通道至 4 通道多路复用器/多路信号分离器

1 特性

- 高带宽(BW = 500MHz, 典型值)
- 低串扰 (X_{TALK} = -30dB, 典型值)
- 具有接近零传播延迟的双向数据流
- 平缓的低导通状态电阻 $(r_{on} = 4\Omega \, \oplus \, \mathbb{Z}_0)$ 中型值, $r_{on(flat)} = 1\Omega$)
- 可在数据 I/O 端口(0 至 5V)上进行开关
- V_{CC} 工作范围为 3V 至 3.6V
- Ioff 支持局部断电模式运行
- 数据和控制输入具有下冲钳位二极管
- 闩锁性能超过 100mA,符合 JESD 78 II 类规范
- ESD 性能测试符合 JESD 22 标准
 - 2000V 人体放电模型 (A114-B, II 类)
 - 1000V 充电器件模型 (C101)
- 适合 10 Base-T 和 100 Base-T 信令

2 应用

• 10 和 100 Base-T 信号开关

3 说明

TS3L110 局域网 (LAN) 开关是一款具有单开关使能端(Ē) 输入的 4 位、2 选 1 多路复用器/多路信号分离器。当 Ē 为低时,开关启用,I 端口连接至 Y 端口。当 Ē 为高时,开关禁用,I 和 Y 端口之间存在高阻抗状态。选择 (S) 输入可控制多路复用器/多路信号分离器的数据路径。

TS3L110 器件可用于代替 LAN 应用中的机械继电器。此器件具有平缓的低导通状态电阻 (ron)、高带宽和低串扰,适合 10/100 Base-T 和各种其他 LAN 应用中的数字输入 D 类音频放大器。TS3L110 器件可用于将信号从 10/100 Base-T 以太网收发器路由至笔记本电脑或扩展坞中的 RJ-45 LAN 连接器。此器件专为低通道间偏差和低串扰而设计。

该器件完全 适用于 I_{off} 为了部分断电的应用。 I_{off} 特性可确保在关断时防止损坏电流通过器件回流。该器件可在关断时提供隔离。

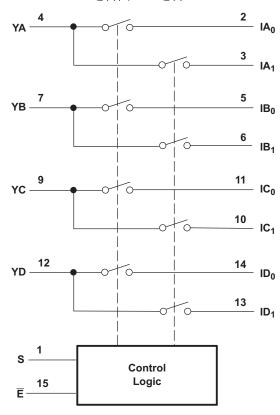
为了确保加电或断电期间的高阻抗状态, $\overline{\mathsf{E}}$ 应通过一个上拉电阻器连接至 V_{CC} ; 该电阻器的最小值由驱动器的电流吸入能力来决定。

器件信息⁽¹⁾

器件型号	封装	封装尺寸 (标称值)
	SOIC (D) 16	9.90mm x 3.91mm
	SSOP (DBQ) 16	4.90mm x 3.90mm
TS3L110	TVSOP (DGV) 16	3.60mm x 4.40mm
	TSSOP (PW) 16	5.00mm x 4.40mm
	VQFN (RGV) 16	4.00mm x 4.00mm

(1) 如需了解所有可用封装,请参阅产品说明书末尾的可订购产品 附录。

逻辑图 (正逻辑)





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4 修订历史记录

注: 之前版本的页码可能与当前版本有所不同。

Changes from Revision A (May 2019) to Revision B

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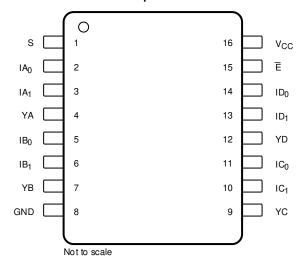
Changes from Original (September 2004) to Revision A

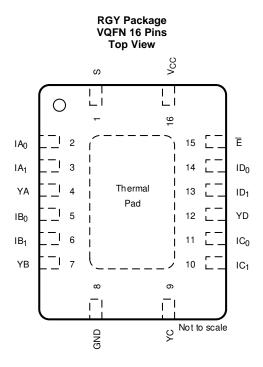
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5 Pin Configuration and Functions

D, DBQ, DGV, or PW Package SOIC, SSOP, TVSOP, TSSOP 16 Pins Top View





Pin Functions

PIN		DESCRIPTION
NAME	NO.	DESCRIPTION
S	1	Select input
IA ₀	2	Data I/Os
IA ₁	3	Data I/Os
YA	4	Data I/Os
IB ₀	5	Data I/Os
IB ₁	6	Data I/Os
YB	7	Data I/Os
GND	8	Ground (0 V) reference
YC	9	Data I/Os
IC ₁	10	Data I/Os
IC ₀	11	Data I/Os
YD	12	Data I/Os
ID ₁	13	Data I/Os
ID ₀	14	Data I/Os
Ē	15	Enable input
V _{CC}	16	Positive power supply. This pin is the most positive power-supply potential. For reliable operation, connect a decoupling capacitor ranging from 0.1 µF to 10 µF between VDD and GND.



6 Specifications

6.1 Absolute Maximum Ratings⁽¹⁾

over operating free-air temperature range (unless otherwise noted)

			MIN	MAX	UNIT
V _{CC}	Supply voltage range				V
V_{IN}	Control input voltage range (2)(3)		-0.5	7	V
V _{I/O}	Switch I/O voltage range (2)(3)(4)		-0.5	7	V
I _{IK}	Control input clamp current	V _{IN} < 0		-50	mA
I _{I/OK}	I/O port clamp current	V _{I/O} < 0		-50	mA
I _{I/O}	ON-state switch current ⁽⁵⁾			±128	mA
	Continuous current through V _{CC} or GND			±100	mA
		D package ⁽⁶⁾		73	
		DBQ package (6)		90	
θ_{JA}	Package thermal impedance	DGV package ⁽⁶⁾		120	°C/W
		PW package ⁽⁶⁾		108	
		RGY package ⁽⁷⁾		39	
T _{stg}	Storage temperature range		-65	150	°C

⁽¹⁾ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) All voltages are with respect to ground, unless otherwise specified.

- 4) V_I and V_O are used to denote specific conditions for $V_{I/O}$.
- (5) I_{l} and I_{O} are used to denote specific conditions for $I_{l/O}$.
- (6) The package thermal impedance is calculated in accordance with JESD 51-7.
- (7) The package thermal impedance is calculated in accordance with JESD 51-5.

6.2 ESD Ratings

			VALUE	UNIT
	Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 (1)	±2000		
V _(ESD)	Electrostatic discharge	Charged-device model (CDM), per JEDEC specification JESD22-C101 or ANSI/ESDA/JEDEC JS-002 (2)	±1000	V

- (1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
- (2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process. e.

6.3 Recommended Operating Conditions (1)

	· ·	MIN	MAX	UNIT
V _{CC}	Supply voltage	3	3.6	V
V_{IH}	High-level control input voltage (E, S)	2	5.5	V
V_{IL}	Low-level control input voltage (E, S)	0	0.8	V
V _{I/O}	Input/output voltage	0	5.5	V
T _A	Operating free-air temperature	-40	85	°C

⁽¹⁾ All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

⁽³⁾ The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.



6.4 Thermal Information

THERMAL METRIC ⁽¹⁾			T\$3L110				
		D (SOIC)	DBQ (SSOP)	DGV (TVSOP)	PW (TSSOP)	RGV (VQFN)	UNIT
		16 PINS	16 PINS	16 PINS	16 PINS	16 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	92.0	114.5	139.3	111.5	50.8	°C/W
R _{0JC(top)}	Junction-to-case (top) thermal resistance	52.3	60.5	57.4	42.0	48.1	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	50.3	58.2	73.7	57.8	26.7	°C/W
ψ_{JT}	Junction-to-top characterization parameter	17.3	15.3	7.2	4.2	2.1	°C/W
ΨЈВ	Junction-to-board characterization parameter	50.0	57.6	73.0	57.2	26.5	°C/W
R _{0JC(bot)}	Junction-to-case (bottom) thermal resistance	-	-	-	-	10.7	°C/W

⁽¹⁾ For more information about traditional and new thermal metrics, see the Semiconductor and IC package thermal metrics application report.

Electrical Characteristics⁽¹⁾ 6.5

over recommended operating free-air temperature range, V_{CC} = 3.3 V ± 0.3 V (unless otherwise noted)

PARAMETER			TEST CONDITIO	ONS	MIN	TYP ⁽²⁾	MAX	UNIT	
V _{IK}	E, S	$V_{CC} = 3.6 \text{ V},$	$I_{IN} = -18 \text{ mA}$				-1.8	V	
I _{IH}	Ē, S	$V_{CC} = 3.6 \text{ V},$	V _{IN} = 5.5 V				±1	μΑ	
I _{IL}	Ē, S	$V_{CC} = 3.6 \text{ V},$	V _{IN} = GND				±1	μΑ	
I _{off}		$V_{CC} = 0$,	$V_{O} = 0 \text{ to } 5.5 \text{ V},$	V _I = 0			1	μΑ	
Icc		$V_{CC} = 3.6 \text{ V},$	$I_{I/O} = 0,$	Switch ON or OFF		0.7	1.5	mA	
C _{in}	E, S	f = 1 MHz,	$V_{IN} = 0$			2.5	3.5	рF	
0	I port	$V_I = 0$,	f = 1 MHz, Outputs open,	Switch OFF		3.5	5		
C _{io(OFF)}	Y port	$V_I = 0$,	f = 1 MHz, Outputs open,	Switch OFF		5.5	7	pF	
C _{io(ON)}	I or Y port	V _I = 0,	f = 1 MHz, Outputs open,	Switch ON		10.5	13	pF	
r _{on}		V _{CC} = 3 V,	$1.25 \text{ V} \leq \text{V}_{\text{I}} \leq \text{V}_{\text{CC}},$	$I_{O} = -10 \text{ mA to } -30 \text{ mA}$		4	8	Ω	
r _{on(flat)} (3)		$V_{CC} = 3 V$,	$V_I = 1.25 \text{ V} \text{ and } V_{CC}$	$I_O = -10$ mA to -30 mA		1		Ω	
$\Delta r_{on}^{(4)}$		V _{CC} = 3 V,	$1.25 \text{ V} \leq \text{V}_{\text{I}} \leq \text{V}_{\text{CC}},$	$I_0 = -10 \text{ mA to } -30 \text{ mA}$		0.9	2	Ω	

 $[\]begin{array}{lll} \text{(1)} & V_{\text{I}}, \, V_{\text{O}}, \, I_{\text{I}}, \, \text{and} \, I_{\text{O}} \, \, \text{refer to I/O pins.} \, \, V_{\text{IN}} \, \, \text{refers to the control inputs.} \\ \text{(2)} & \, \text{All typical values are at V}_{\text{CC}} = 3.3 \, \, \text{V} \, \, \text{(unless otherwise noted)}, \, T_{\text{A}} = 25 ^{\circ} \text{C}. \\ \text{(3)} & \, r_{\text{on}(\text{flat})} \, \, \text{is the difference of r}_{\text{on}} \, \, \text{in a given channel at specified voltages.} \\ \text{(4)} & \, \Delta r_{\text{on}} \, \, \text{is the difference of r}_{\text{on}} \, \, \text{in a given device.} \\ \end{array}$



Switching Characteristics

over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V, R_L = 200 Ω , C_L = 10 pF (unless otherwise noted) (see Figure 5 and Figure 6)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN	TYP ⁽¹⁾	MAX	UNIT
$t_{pd}^{(2)}$	I or Y	Y or I		0.25		ns
t _{PZH} , t _{PZL}	E or S	I or Y	0.5		7	ns
t _{PHZ} , t _{PLZ}	E or S	I or Y	0.5		5	ns
$t_{sk(p)}^{(3)}$	I or Y	Y or I		0.1	0.2	ns

Dynamic Characteristics 6.7

over recommended operating free-air temperature range, V_{CC} = 3.3 V ± 0.3 V (unless otherwise noted)

PARAMETER		TEST CONDITIONS			
X _{TALK}	$R_L = 100 \Omega$,	f = 250 MHz,	See Figure 7	-26	dB
O _{IRR}	$R_L = 100 \Omega$,	f = 250 MHz,	See Figure 8	-28	dB
BW	$R_L = 100 \Omega$,		See Figure 6	500	MHz

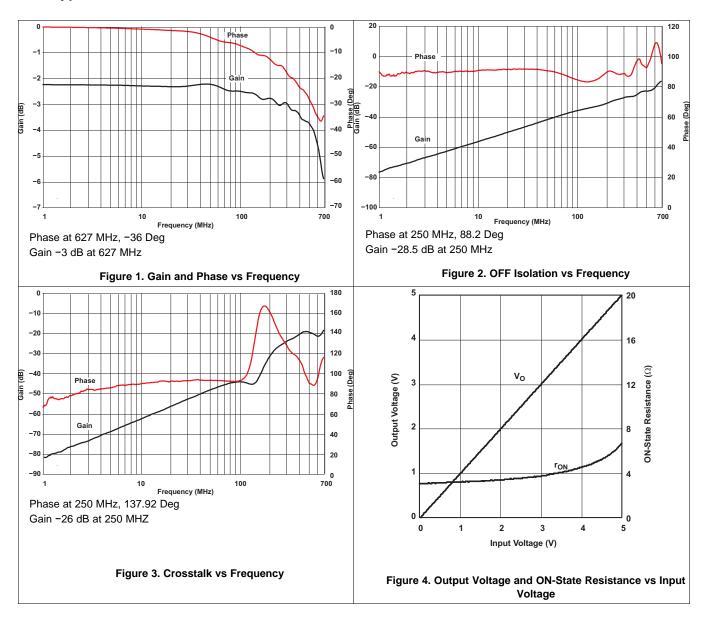
⁽¹⁾ All typical values are at V_{CC} = 3.3 V (unless otherwise noted), T_A = 25°C.

 ⁽¹⁾ All typical values are at V_{CC} = 3.3 V (unless otherwise noted), T_A = 25°C.
 (2) The propagation delay is the calculated RC time constant of the typical ON-state resistance of the switch and the specified load capacitance when driven by an ideal voltage source (zero output impedance).

⁽³⁾ Skew between opposite transitions of the same output |tpHL - tpLH|. This parameter is not production tested.

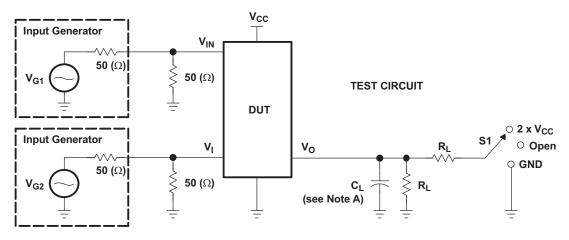


6.8 Typical Characteristics

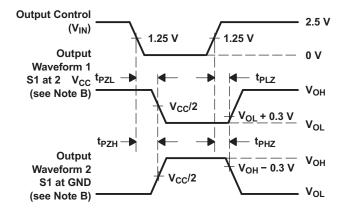




7 Parameter Measurement Information



TEST	V _{CC}	S1	R_L	VI	CL	$oldsymbol{V}_\Delta$
t _{PLZ} /t _{PZL}	3.3 V \pm 0.3 V	2 x V _{CC}	200 (Ω)	GND	10 pF	0.3 V
t _{PHZ} /t _{PZH}	3.3 V ± 0.3 V	GND	200 (Ω)	V _{CC}	10 pF	0.3 V

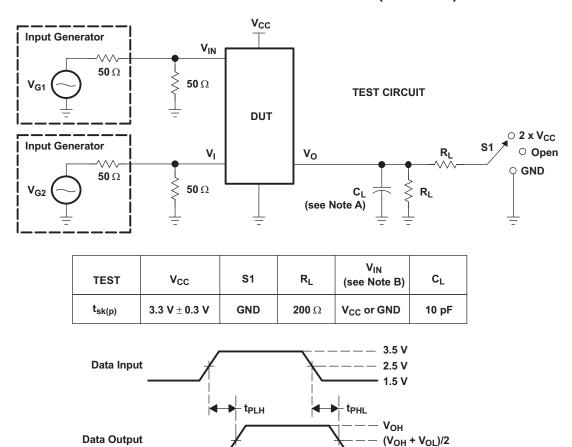


VOLTAGE WAVEFORMS ENABLE AND DISABLE TIMES

- A. C_L includes probe and jig capacitance.
- B. Waveform 1 is for an output with internal conditions such that the output is low. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50 \Omega$, $t_r \leq$ 2.5 ns, $t_r \leq$ 2.5 ns
- D. The outputs are measured one at a time, with one transition per measurement.
- E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
- F. t_{PLZ} and t_{PHH} are the same as t_{en} .

Figure 5. Test Circuit and Voltage Waveforms





VOLTAGE WAVEFORMS PULSE SKEW $[t_{sk(p)}]$

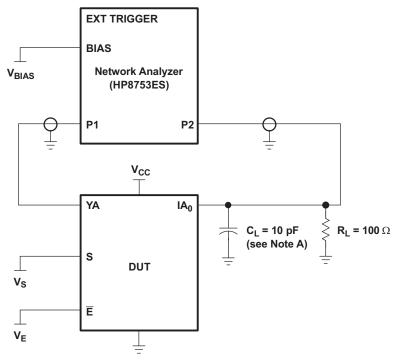
 $t_{sk(p)} = t_{PHL} - t_{PLH}$

- A. C_L includes probe and jig capacitance.
- B. Switch is ON during the measurement of $t_{sk(p)}$, that is, voltage at E = 0 and S = V_{CC} or GND.

Figure 6. Test Circuit and Voltage Waveforms

 V_{OL}





A. C_L includes probe and jig capacitance.

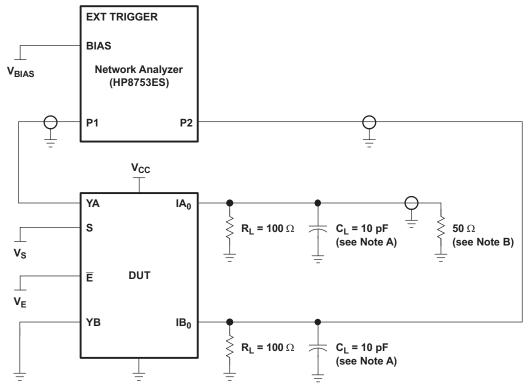
Figure 7. Test Circuit for Frequency Response (BW)

Frequency response is measured at the output of the ON channel. For example, when $V_S = 0$, $V_E = 0$, and YA is the input, the output is measured at IA $_0$. All unused analog I/O ports are left open.

HP8753ES Setup

- Average = 4
- RBW = 3 kHz
- $V_{BIAS} = 0.35 \text{ V}$
- ST = 2 s
- P1 = 0 dBM





- C_L includes probe and jig capacitance.
- B. A $50-\Omega$ termination resistor is needed to match the loading of the network analyzer

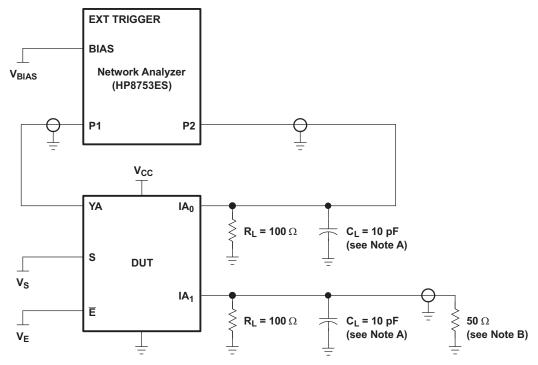
Figure 8. Test Circuit for Crosstalk (X_{TALK})

Crosstalk is measured at the output of the nonadjacent ON channel. For example, when $V_S=0$, $V_E=0$, and YA is the input, the output is measured at IB_0 . All unused analog input (Y) ports are connected to GND, and output (I) ports are connected to GND through 50- Ω pulldown resistors.

HP8753ES Setup

- Average = 4
- RBW = 3 kHz
- $V_{BIAS} = 0.35 \text{ V}$
- ST = 2 s
- P1 = 0 dBM





- A. C_L includes probe and jig capacitance.
- B. A $50-\Omega$ termination resistor is needed to match the loading of the network analyzer

Figure 9. Test Circuit for OFF Isolation (OIRR)

OFF isolation is measured at the output of the OFF channel. For example, when $V_S = V_{CC}$, $V_E = 0$, and YA is the input, the output is measured at IA₀. All unused analog input (Y) ports are left open, and output (I) ports are connected to GND through $50-\Omega$ pulldown resistors.

HP8753FS Setup

- Average = 4
- RBW = 3 kHz
- V_{BIAS} = 0.35 V
- ST = 2 s
- P1 = 0 dBM

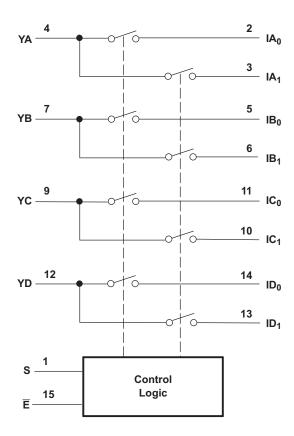


8 Detailed Description

8.1 Overview

The TI TS3L110 LAN switch is a 4-bit 1-of-2 multiplexer/demultiplexer with a single switch-enable (E) input. When E is low, the switch is enabled, and the I port is connected to the Y port. When E is high, the switch is disabled, and the high-impedance state exists between the I and Y ports. The select (S) input controls the data path of the multiplexer/demultiplexer.

8.2 Functional Block Diagram



8.3 Feature Description

I_{off} supports Partial-Power-Down Mode Operation.

The TS3L110 device ensures the signal path is high impedance state when $V_{CC} = 0 \text{ V}$.

8.4 Device Functional Modes

The TS3L110 supports a power down mode which reduces the current consumption of the device and places all the signal paths in a high impedance state. To place the TS3L100 in power down mode, set the \overline{E} pin with a logic high voltage as seen in Table 1.

Table 1. Function Table

INPUTS		INPUT/OUTPUT	FUNCTION		
Ē	S	YX	FUNCTION		
L	L	IX ₀	$YX = IX_0$		
L	Н	IX ₁	$YX = IX_1$		
Н	Х	Z	Disconnect		



9 Application and Implementation

NOTE

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

9.1 Application Information

There are many Local Area Network (LAN) applications in which the ethernet hubs or controllers have a limited number of I/Os or need to route signals from a single ethernet PHY to multiple ethernet jacks. The TS3L110 solution can effectively expand the limited I/Os by switching between multiple Ethernet jacks to interface them to a single Ethernet PHY.

9.2 Typical Application

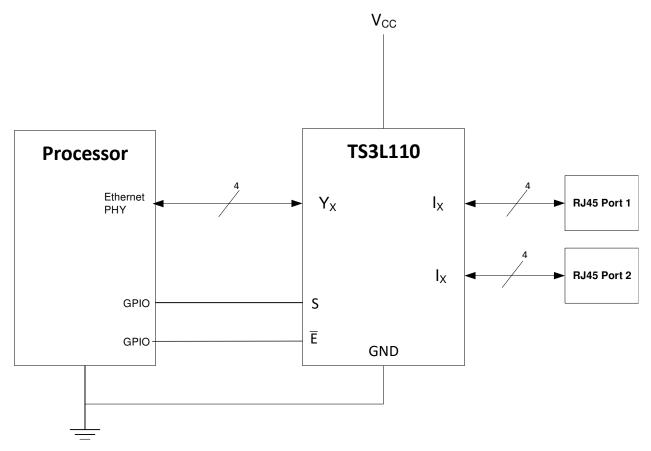


Figure 10. Typical Application Schematic

9.2.1 Design Requirements

Ensure that all of the signals passing through the switch are within the recommended operating ranges. To ensure proper performance, see Recommended Operating Conditions.

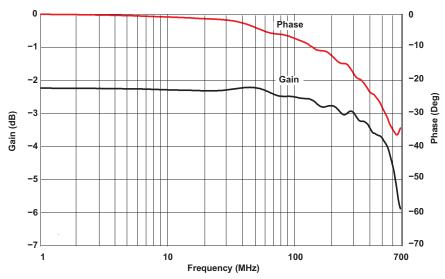
9.2.2 Detailed Design Procedure

The TS3L110 can be properly operated without any external components. TI recommends that the digital control pins S and \overline{E} be pulled up to VCC or down to GND to avoid undesired switch positions that could result from the floating pin. Connect the exposed thermal pad to ground.



Typical Application (continued)

9.2.3 Application Curves



Phase at 627 MHz, -36 Deg Gain -3 dB at 627 MHz

Figure 11. Gain and Phase vs Frequency

10 Power Supply Recommendations

Power to the device is supplied through the VCC pins. TI recommends placing a bypass capacitor as close to the supply pin (VCC) as possible to help smooth out lower frequency noise to provide better load regulation across the frequency spectrum.



11 Layout

11.1 Layout Guidelines

- TI recommends keeping the high-speed signals as short as possible.
- Each via introduces discontinuities in the transmission line of the signal and increases the chance of picking up interference from the other layers of the board. Be careful when designing test points on twisted pair lines; through-hole pins are not recommended.
- When it becomes necessary to turn 90°, use two 45° turns or an arc instead of making a single 90° turn. This reduces reflections on the signal traces by minimizing impedance discontinuities.
- Do not route traces under or near crystals, oscillators, clock signal generators, switching regulators, mounting holes, magnetic devices or ICs that use or duplicate clock signals.
- Avoid stubs on the high-speed signals because they cause signal reflections. If a stub is unavoidable, then
 the stub must be less than 200 mm.
- Route all high-speed signal traces over continuous GND planes, with no interruptions. Avoid crossing over anti-etch, commonly found with plane splits.
- Due to high-frequency signals, a printed-circuit board with at least four layers is recommended; two signal layers separated by a ground and power layer as shown in Figure 12.
- The majority of signal traces must run on a single layer, preferably Signal 1. Immediately next to this layer should be the GND plane, which is solid with no cuts. Avoid running signal traces across a split in the ground or power plane. When running across split planes is unavoidable, sufficient decoupling must be used. Minimizing the number of signal vias reduces EMI by reducing inductance at high frequencies.

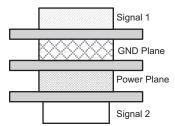


Figure 12. Four-Layer Board Stackup



11.2 Layout Example

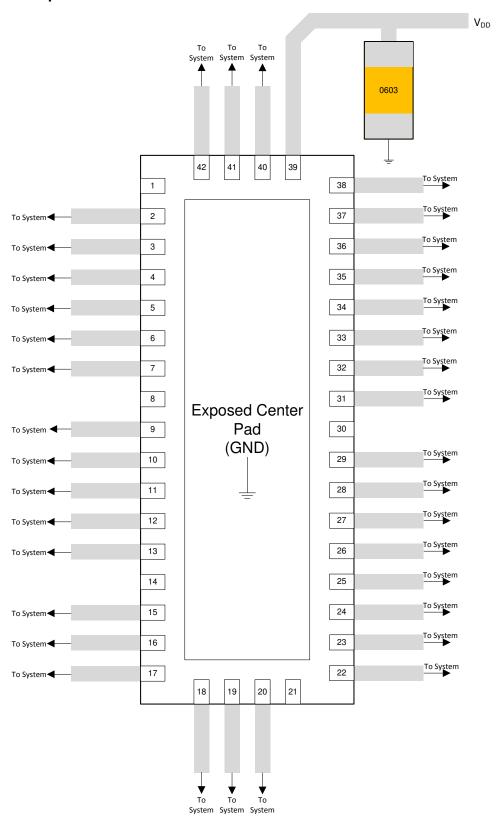


Figure 13. Layout Example



12 器件和文档支持

12.1 接收文档更新通知

要接收文档更新通知,请导航至 ti.com. 上的器件产品文件夹。单击右上角的通知我进行注册,即可每周接收产品 信息更改摘要。有关更改的详细信息,请查看任何已修订文档中包含的修订历史记录。

12.2 社区资源

TI E2E™ support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

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12.3 商标

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静电放电警告



ESD 可能会损坏该集成电路。德州仪器 (TI) 建议通过适当的预防措施处理所有集成电路。如果不遵守正确的处理措施和安装程序,可 能会损坏集成电路。



ESD 的损坏小至导致微小的性能降级,大至整个器件故障。 精密的集成电路可能更容易受到损坏,这是因为非常细微的参数更改都可 能会导致器件与其发布的规格不相符。

12.5 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

13 机械、封装和可订购信息

以下页面包含机械、封装和可订购信息。这些信息是指定器件的最新可用数据。数据如有变更,恕不另行通知,且 不会对此文档进行修订。如需获取此数据表的浏览器版本,请查阅左侧的导航栏。

10-Nov-2025

www.ti.com

PACKAGING INFORMATION

Orderable part number	Status	Material type	Package Pins	Package qty Carrier	RoHS (3)	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
						(4)	(5)		
TS3L110D	Active	Production	SOIC (D) 16	40 TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TS3L110
TS3L110D.B	Active	Production	SOIC (D) 16	40 TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TS3L110
TS3L110DBQR	Active	Production	SSOP (DBQ) 16	2500 LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	TK110
TS3L110DBQR.B	Active	Production	SSOP (DBQ) 16	2500 LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	TK110
TS3L110DBQRG4	Active	Production	SSOP (DBQ) 16	2500 LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	TK110
TS3L110DBQRG4.B	Active	Production	SSOP (DBQ) 16	2500 LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	TK110
TS3L110DE4	Active	Production	SOIC (D) 16	40 TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TS3L110
TS3L110DG4	Active	Production	SOIC (D) 16	40 TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TS3L110
TS3L110DGVR	Active	Production	TVSOP (DGV) 16	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TK110
TS3L110DGVR.B	Active	Production	TVSOP (DGV) 16	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TK110
TS3L110DR	Active	Production	SOIC (D) 16	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TS3L110
TS3L110DR.B	Active	Production	SOIC (D) 16	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TS3L110
TS3L110PW	Obsolete	Production	TSSOP (PW) 16	-	-	Call TI	Call TI	-40 to 85	TK110
TS3L110PWR	Active	Production	TSSOP (PW) 16	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TK110
TS3L110PWR.B	Active	Production	TSSOP (PW) 16	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TK110
TS3L110RGYR	Active	Production	VQFN (RGY) 16	3000 LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	TK110
TS3L110RGYR.B	Active	Production	VQFN (RGY) 16	3000 LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	TK110
TS3L110RGYRG4	Active	Production	VQFN (RGY) 16	3000 LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	TK110
TS3L110RGYRG4.B	Active	Production	VQFN (RGY) 16	3000 LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	TK110

⁽¹⁾ Status: For more details on status, see our product life cycle.

⁽²⁾ **Material type:** When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

⁽⁴⁾ Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.



PACKAGE OPTION ADDENDUM

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(5) MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

(6) Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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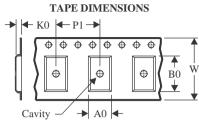
In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

PACKAGE MATERIALS INFORMATION

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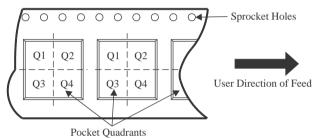
TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

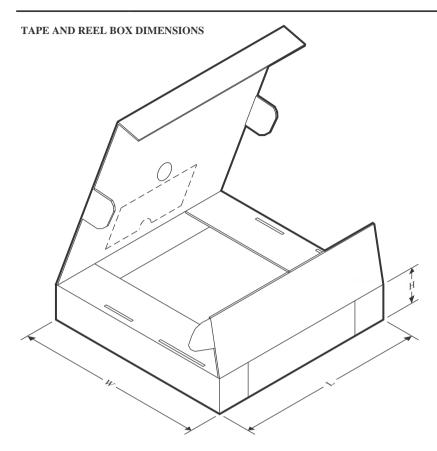


*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TS3L110DBQR	SSOP	DBQ	16	2500	330.0	12.5	6.4	5.2	2.1	8.0	12.0	Q1
TS3L110DBQRG4	SSOP	DBQ	16	2500	330.0	12.5	6.4	5.2	2.1	8.0	12.0	Q1
TS3L110DGVR	TVSOP	DGV	16	2000	330.0	12.4	6.8	4.0	1.6	8.0	12.0	Q1
TS3L110DR	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
TS3L110PWR	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
TS3L110RGYR	VQFN	RGY	16	3000	330.0	12.4	3.8	4.3	1.5	8.0	12.0	Q1
TS3L110RGYRG4	VQFN	RGY	16	3000	330.0	12.4	3.8	4.3	1.5	8.0	12.0	Q1



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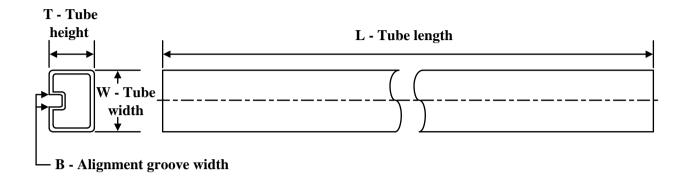
*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TS3L110DBQR	SSOP	DBQ	16	2500	353.0	353.0	32.0
TS3L110DBQRG4	SSOP	DBQ	16	2500	353.0	353.0	32.0
TS3L110DGVR	TVSOP	DGV	16	2000	353.0	353.0	32.0
TS3L110DR	SOIC	D	16	2500	340.5	336.1	32.0
TS3L110PWR	TSSOP	PW	16	2000	353.0	353.0	32.0
TS3L110RGYR	VQFN	RGY	16	3000	353.0	353.0	32.0
TS3L110RGYRG4	VQFN	RGY	16	3000	353.0	353.0	32.0

PACKAGE MATERIALS INFORMATION

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TUBE



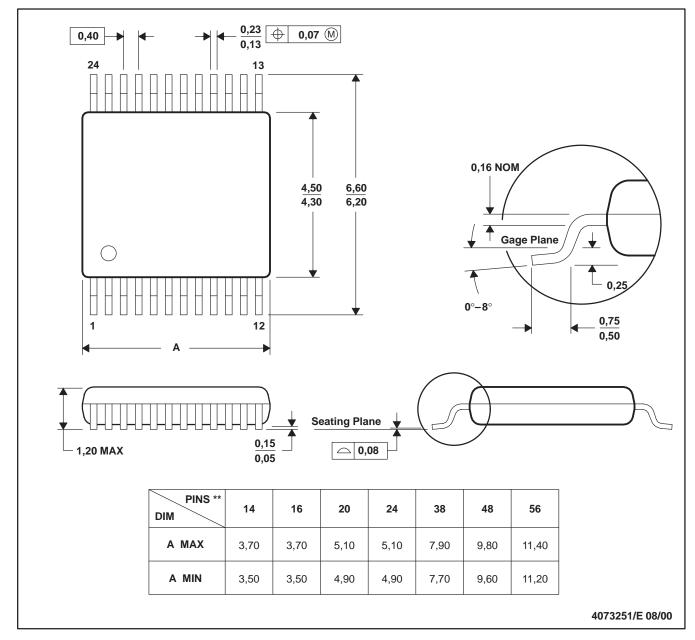
*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
TS3L110D	D	SOIC	16	40	507	8	3940	4.32
TS3L110D.B	D	SOIC	16	40	507	8	3940	4.32
TS3L110DE4	D	SOIC	16	40	507	8	3940	4.32
TS3L110DG4	D	SOIC	16	40	507	8	3940	4.32

DGV (R-PDSO-G**)

24 PINS SHOWN

PLASTIC SMALL-OUTLINE



NOTES: A. All linear dimensions are in millimeters.

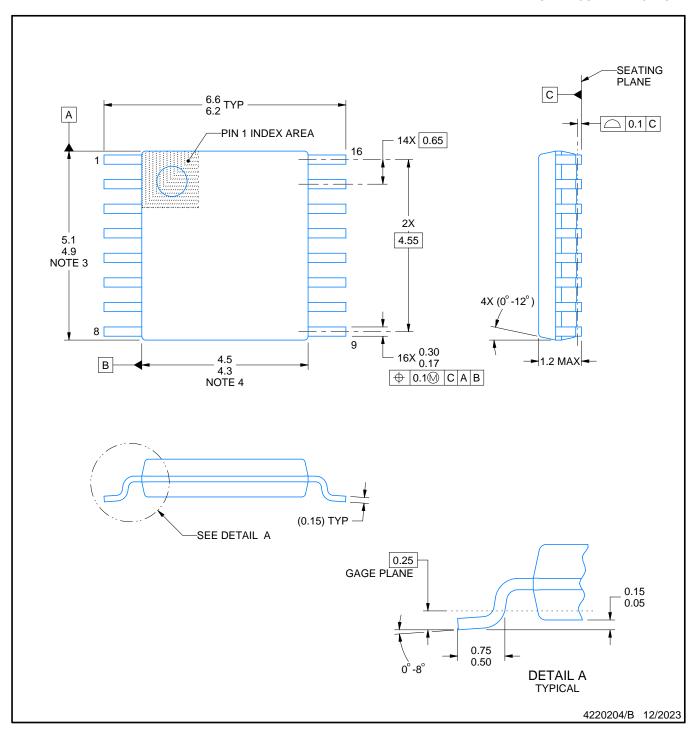
B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion, not to exceed 0,15 per side.

D. Falls within JEDEC: 24/48 Pins – MO-153 14/16/20/56 Pins – MO-194



SMALL OUTLINE PACKAGE



NOTES:

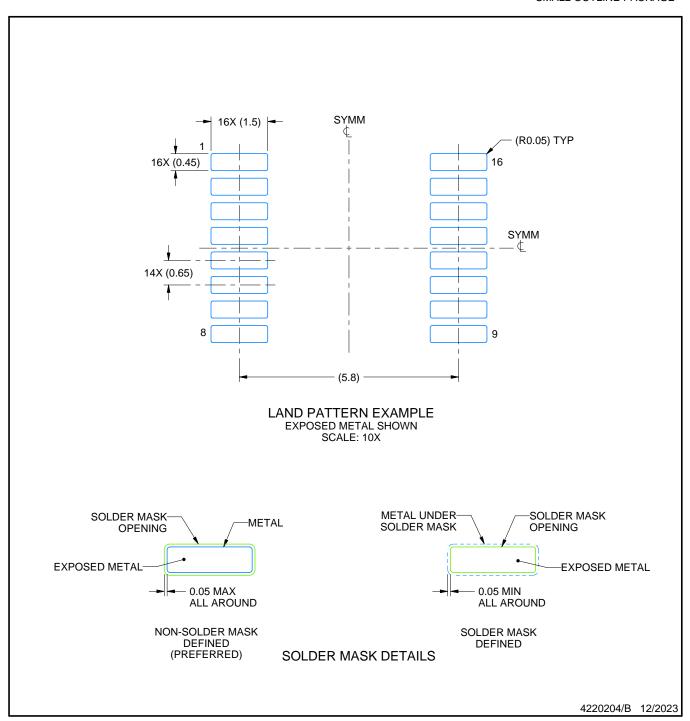
- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



SMALL OUTLINE PACKAGE

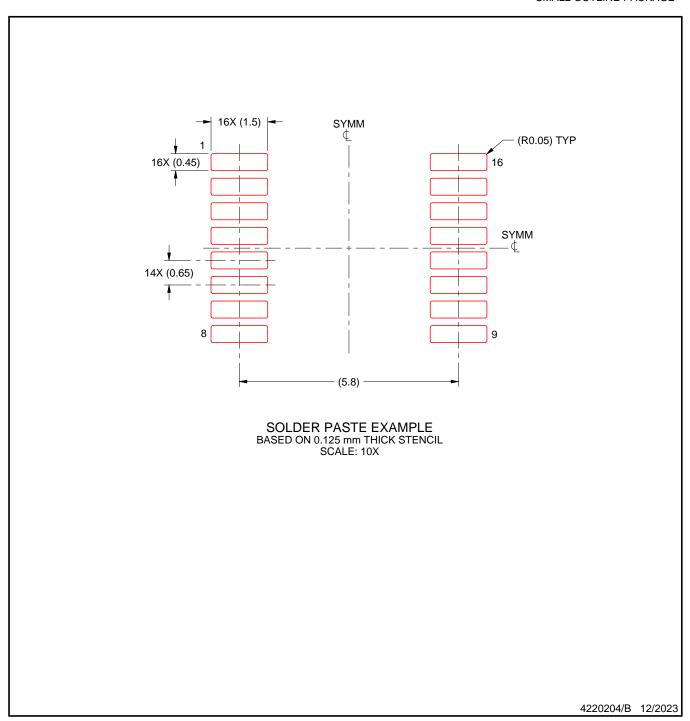


NOTES: (continued)

- 6. Publication IPC-7351 may have alternate designs.
- 7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



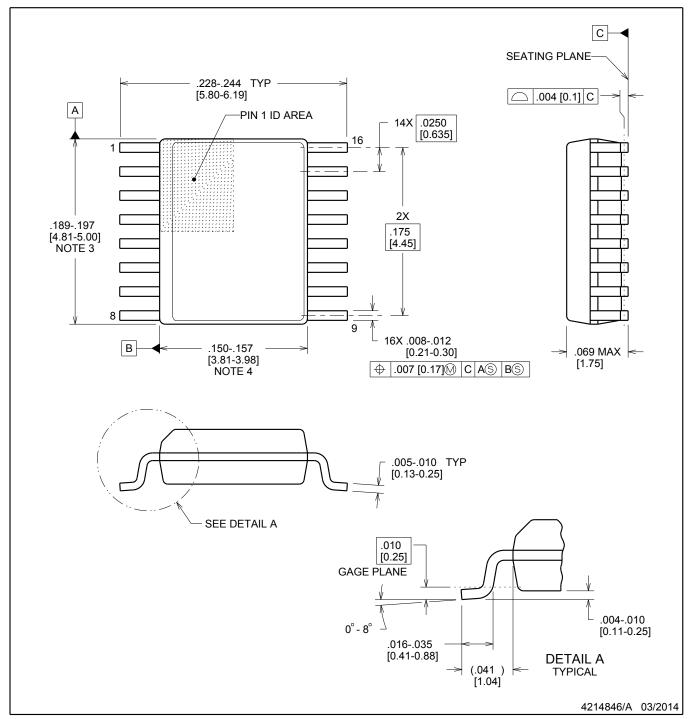
NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.





SHRINK SMALL-OUTLINE PACKAGE

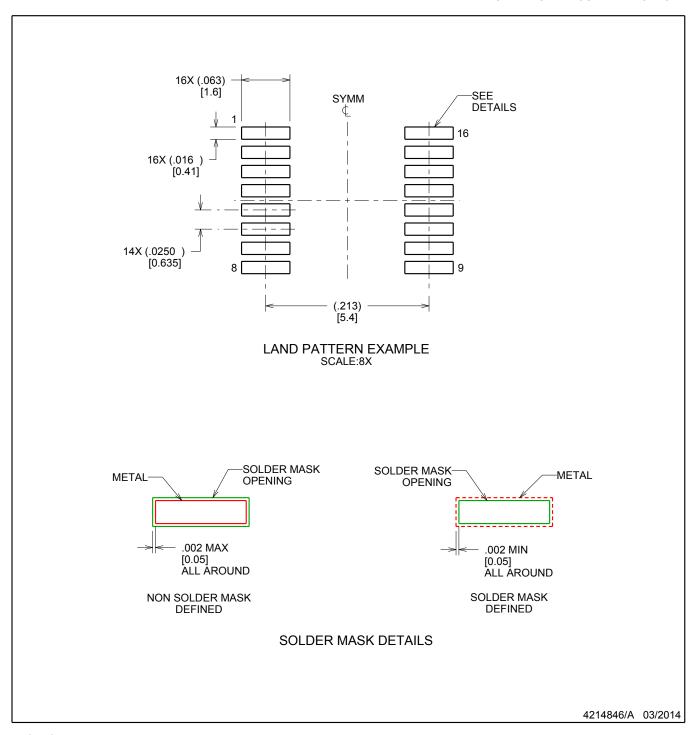


NOTES:

- 1. Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 inch, per side.
- 4. This dimension does not include interlead flash.5. Reference JEDEC registration MO-137, variation AB.



SHRINK SMALL-OUTLINE PACKAGE



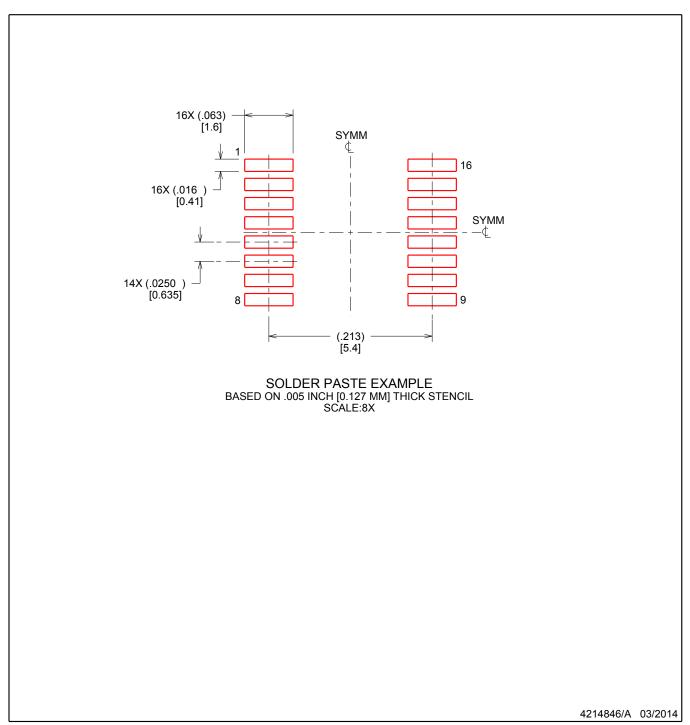
NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



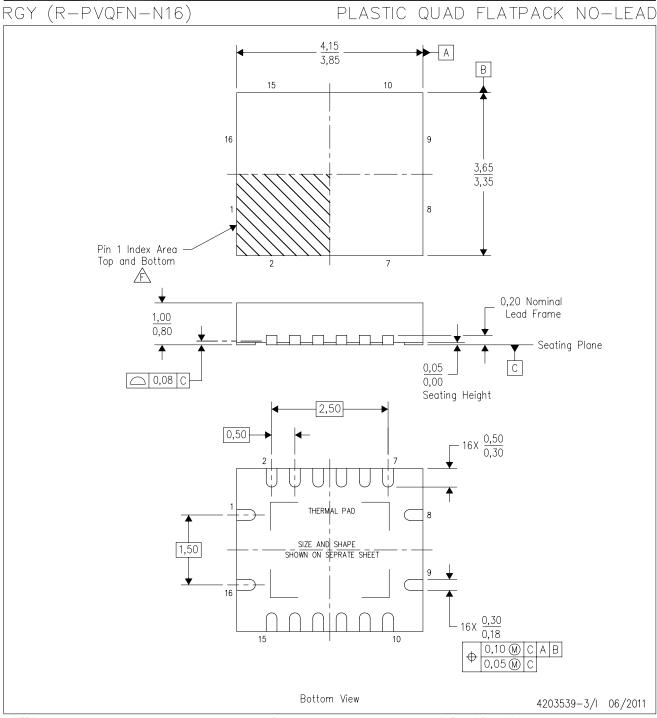
SHRINK SMALL-OUTLINE PACKAGE



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.





NOTES: A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. QFN (Quad Flatpack No-Lead) package configuration.
- D. The package thermal pad must be soldered to the board for thermal and mechanical performance.
- E. See the additional figure in the Product Data Sheet for details regarding the exposed thermal pad features and dimensions.
- Pin 1 identifiers are located on both top and bottom of the package and within the zone indicated. The Pin 1 identifiers are either a molded, marked, or metal feature.
- G. Package complies to JEDEC MO-241 variation BA.



RGY (R-PVQFN-N16)

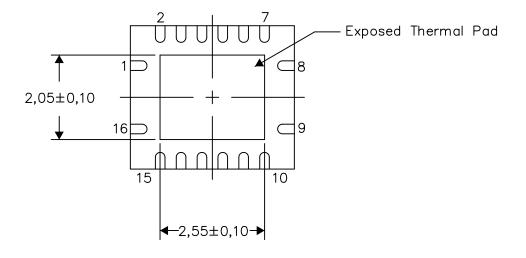
PLASTIC QUAD FLATPACK NO-LEAD

THERMAL INFORMATION

This package incorporates an exposed thermal pad that is designed to be attached directly to an external heatsink. The thermal pad must be soldered directly to the printed circuit board (PCB). After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For information on the Quad Flatpack No-Lead (QFN) package and its advantages, refer to Application Report, QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271. This document is available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.



Bottom View

Exposed Thermal Pad Dimensions

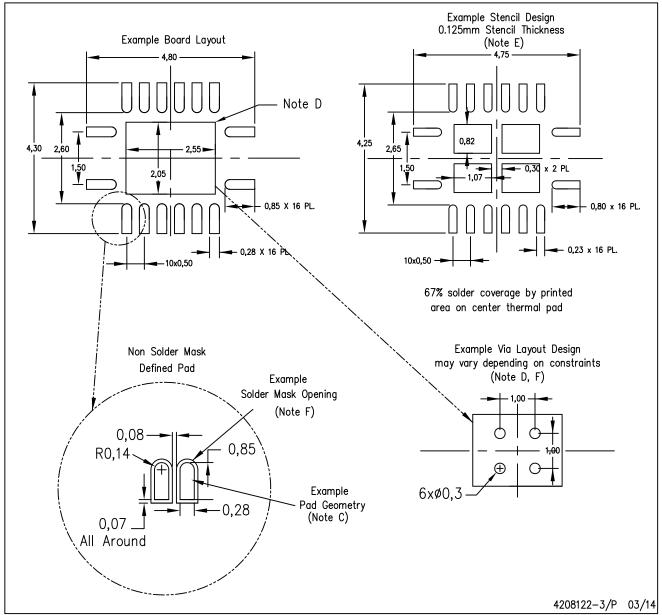
4206353-3/P 03/14

NOTE: All linear dimensions are in millimeters



RGY (R-PVQFN-N16)

PLASTIC QUAD FLATPACK NO-LEAD



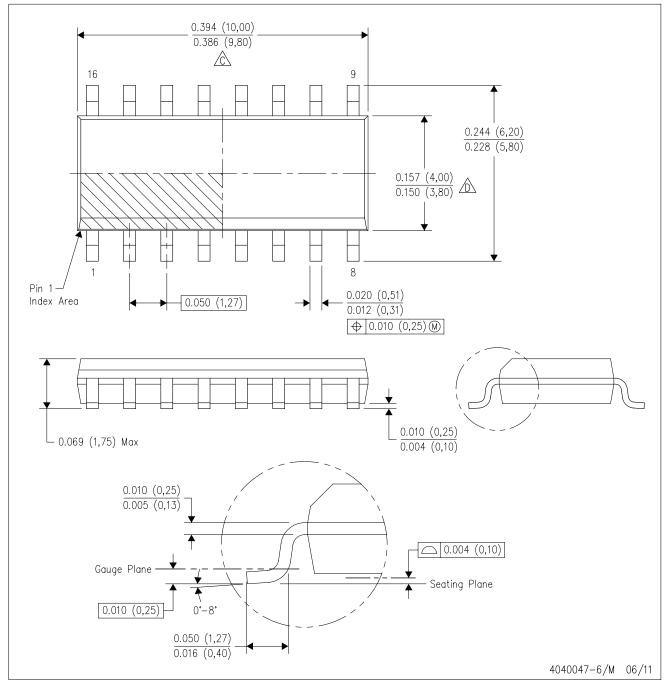
NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. This package is designed to be soldered to a thermal pad on the board. Refer to Application Note, Quad Flat—Pack QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271, and also the Product Data Sheets for specific thermal information, via requirements, and recommended board layout. These documents are available at www.ti.com http://www.ti.com.
- E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations.
- F. Customers should contact their board fabrication site for minimum solder mask web tolerances between signal pads.



D (R-PDS0-G16)

PLASTIC SMALL OUTLINE



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AC.



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